

**Search Notes**


Application No.

10/608,263

Examiner

Bernard E Souw

Applicant(s)

HASHIMOTO ET AL.

Art Unit

2881

**SEARCHED**

Class	Subclass	Date	Examiner
250	282	12/03/03	BES
1	292		
	290		
280	281		
Updated 05/15/04 BES			

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(ion trap) (mass Spectrometer) + (gas) introduct	12/03/01	BES
(inlet or orifice or hole or opening or port) +		
(AC or RF or supple- ment) voltage max (band band or frequency scan)		
(var) or + dissociat		
+ (endcap or ring) electrode		
Updated	05/15/04	BES

**Search Notes**

Applicati n No.

10/608,263

Examin r

Bernard E Souw

Applicant(s)

HASHIMOTO ET AL.

Art Unit

2881

**SEARCHED**

Class	Subclass	Date	Examiner
250	292, 286	5/15/2004	BES
250	281-283	5/15/2004	BES
250	290, 293	5/15/2004	BES

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
250	281-293	5/15/2004	BES

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
see attached		